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United States Patent [19]

Kerschner et al.

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[45] **Date of Patent: ** Feb. 8, 1994**

[54] **CAPACITIVE TEST PROBE BOARD**

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[73] Assignee: **Hewlett-Packard Company,** Palo Alto, Calif.

[**] Term: **14 Years**

[21] Appl. No.: **1,921**

[22] Filed: **Nov. 25, 1992**

[52] U.S. Cl. **D10/80**

[58] **Field of Search** .... 73/864.01; 29/401; 324/158 F, 158 P, 72.5, 537, 678, 690; D10/74, 80; D13/199

[56] **References Cited**

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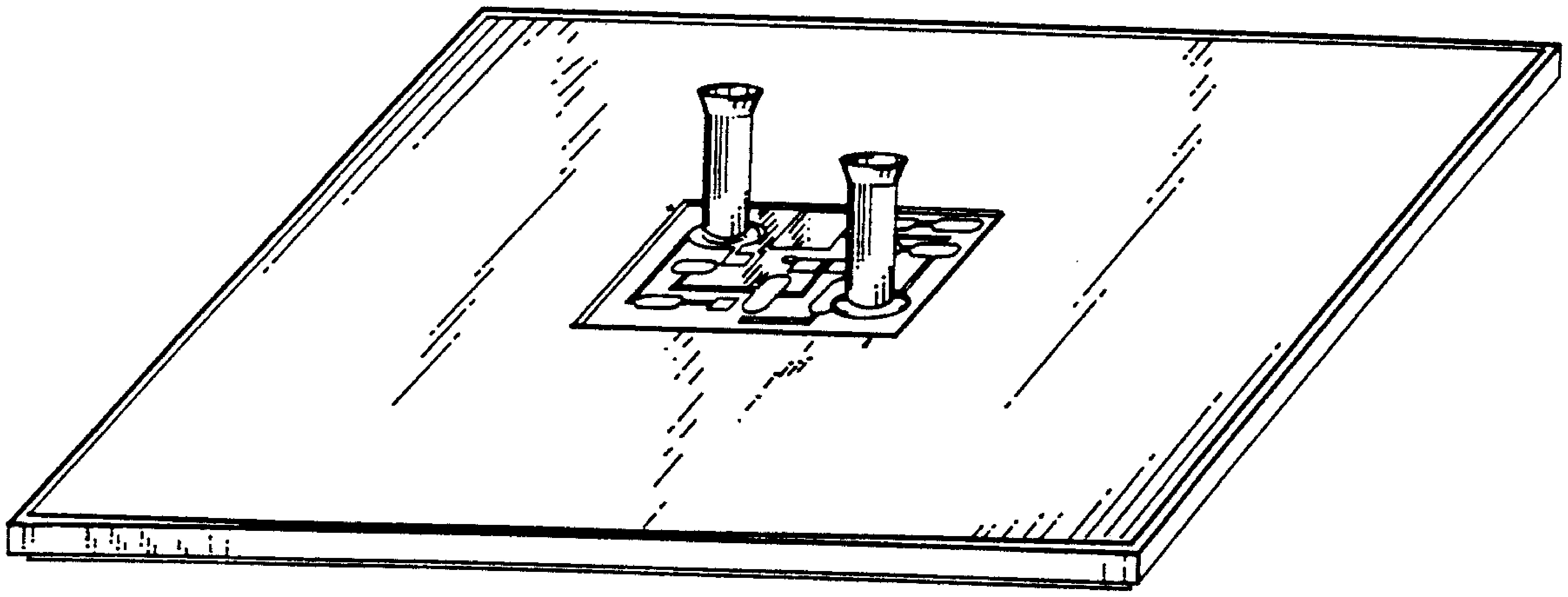
Primary Examiner—Alan P. Douglas
Assistant Examiner—Antoine D. Davis

[57] **CLAIM**

The ornamental design for a capacitive test probe board, as shown and described.

DESCRIPTION

FIG. 1 is a top, front perspective view of a capacitive test probe board showing our new design;
FIG. 2 is a top plan view thereof;
FIG. 3 is a rear elevation view thereof;
FIG. 4 is a front elevation view thereof;
FIG. 5 is a left side elevation view thereof;
FIG. 6 is a right side elevation view thereof; and,
FIG. 7 is a bottom plan view thereof.



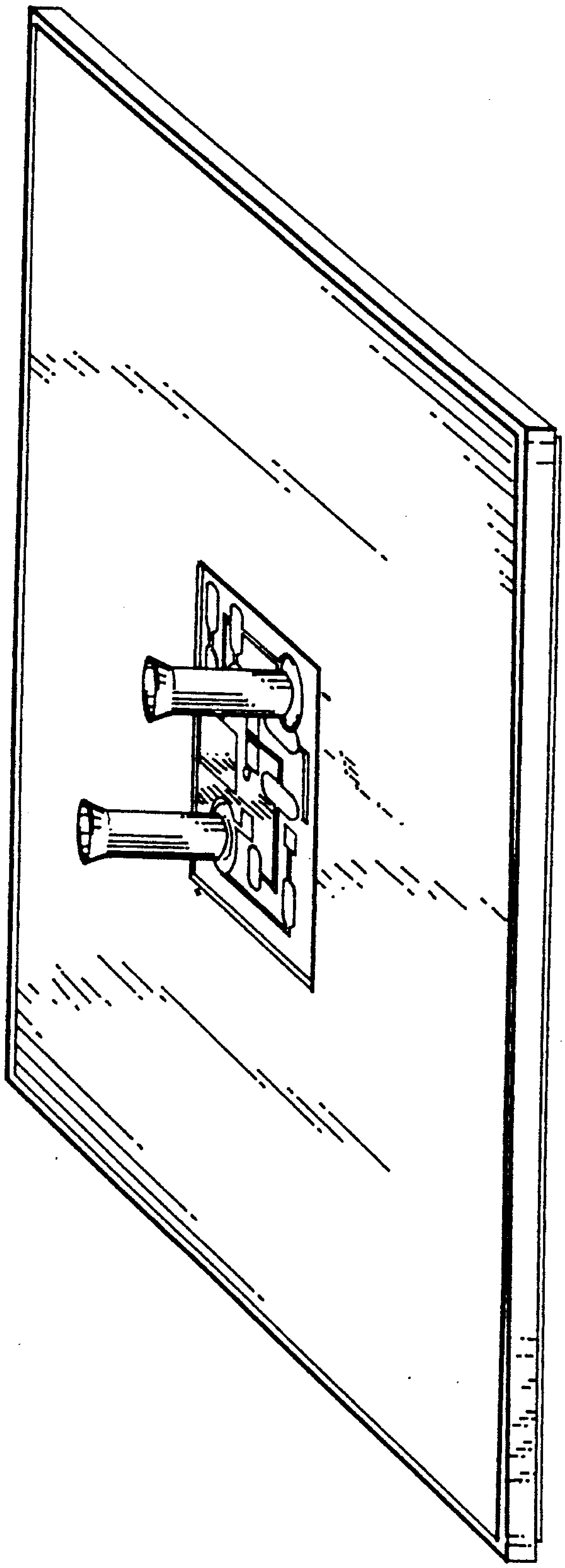
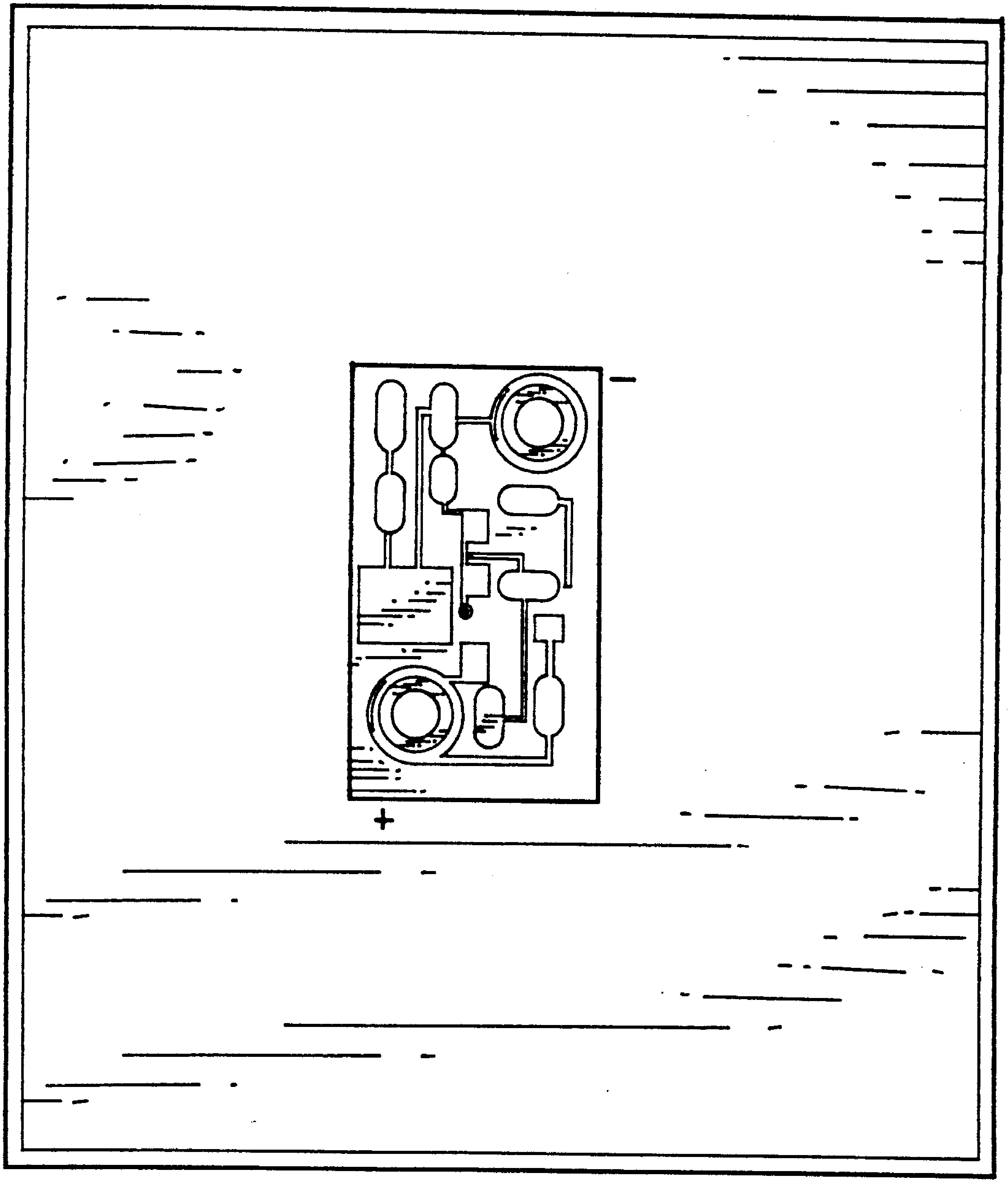


FIG 1

FIG 2



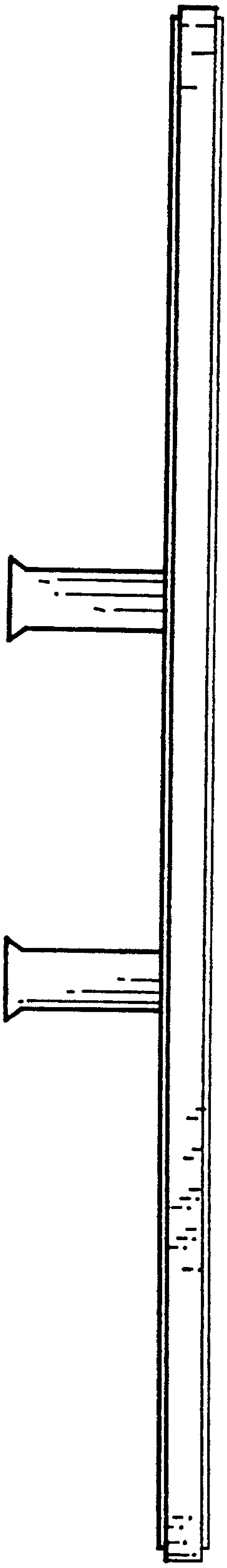


FIG 3

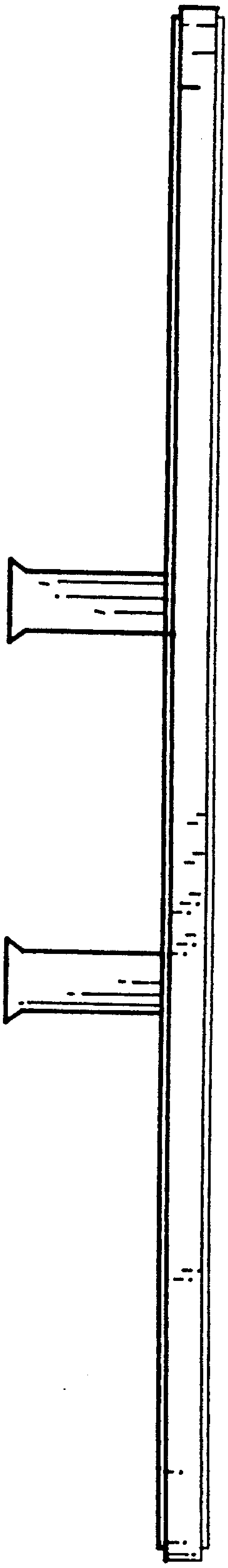


FIG 4

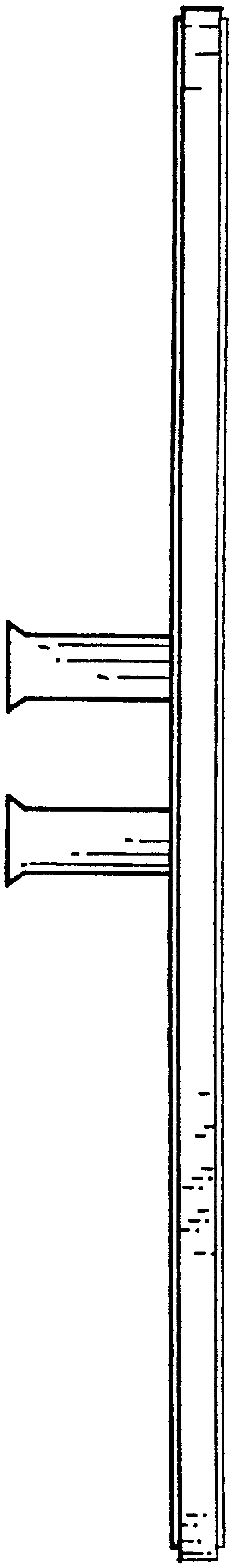


FIG 5

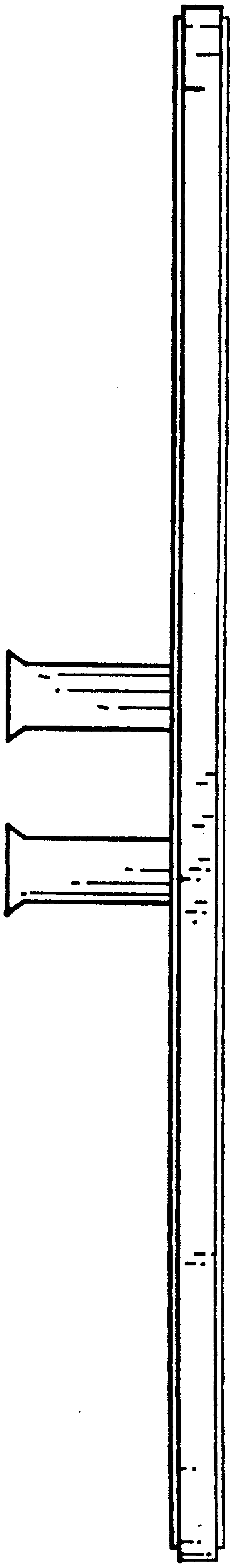


FIG 6

FIG 7